| DOUBLE 1 12 2017 | | | | | | | | | |
|--|--------------|-----------|--------------------|--|------|---------------------|--------------------|------|--|
| PCN Number: 20170207002 PCN Date: Feb 13, 20 | | | | | | | | | |
| Title: Qualification of AMKOR P3 as Additional Assembly and Test Site for Select VSON-CLIP Package Devices | | | | | | | | | |
| Customer Contact: PCN Manager Dept: Quality Services | | | | | | | | | |
| Proposed 1 st Ship Date: May 13 | | May 13, | 2017 | Estimated Sample Date provided at Availability: sample request | | | | | |
| Change Type: | | | | | | | | | |
| | | | Design | ☐ Wafer Bump Site | | | | | |
| Assembly Prod | cess | | Data S | | | | fer Bump Material | | |
| Assembly Mat | erials | | Part number change | | | Wafe | Wafer Bump Process | | |
| Mechanical Sp | ecification | | | | | Wafe | Wafer Fab Site | | |
| Packing/Shipp | oing/Labelir | ng | Test Process | | Wafe | Wafer Fab Materials | | | |
| | | | | | | Wafe | Wafer Fab Process | | |
| | | | PCN | l Details | | | | | |
| Description of Ch | nange: | | | | | | | | |
| Texas Instruments Incorporated is announcing the qualification of AMKOR P3 as Additional Assembly and Test Site for select devices listed in the "Product Affected" Section. Current assembly sites and Material differences are as follows. | | | | | | | | | |
| Assembly Site A | ssembly Si | te Origin | Assemb | ly Country Code | 1 | Assembly | Site Ci | ty | |
| TI Clark | QAB | | | PHL | An | geles City | , Pampa | anga | |
| Amkor P3 | AP3 | ı | | PHL | | Biñan, I | Biñan, Laguna | | |
| Material Differen | ices: | | | | | | | | |
| | | TI Clar | k | AMKOR P3 | 3 | | | | |
| Mold compoun | ıd | 420862 | | | | | | | |
| Lead finish | | NiPdA | ı | Matte Sn | | | | | |
| Test coverage, insertions, conditions will remain consistent with current testing and verified with test MQ. | | | | | | | | | |
| Reason for Change: | | | | | | | | | |
| Continuity of supply. | | | | | | | | | |
| Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative): | | | | | | | | | |
| None | | | | | | | | | |
| Anticipated impact on Material Declaration | | | | | | | | | |
| No Impact to the Material Declaration Product Content reports are driven from production data and will be available following the production release. Upon production release the revised reports can be obtained from the TI ECO website. | | | | | | | | | |
| Changes to product identification resulting from this PCN: | | | | | | | | | |

Sample product shipping label (not actual product label)

Assembly Site:

| TI-CLARK | Assembly Site Origin (22L) | ASO: QAB | ECAT: E4 |
|----------|----------------------------|----------|----------|
| AMKOR P3 | Assembly Site Origin (22L) | ASO: AP3 | ECAT: E3 |

Sample product shipping label to show code location (not actual product label)



ECAT: E4 = NiPdAu ECAT: E3 = Matte Sn

(1P) \$N74L\$07N\$R (Q) 2000 (D) 0336 (31T)LOT: 3959047MLA (4W) TKY(1T) 7523483812

(2P) REV: (V) 0033317 (20L) CSO: SHE (21L) CCO:USA (22L) ASO: MLA (23L) ACO: MYS

ASSEMBLY SITE CODES: TI-CLARK = I , AP3 = 3

Product Affected:

| CSD58899Q3D | CSD87333Q3DT | CSD87334Q3DT | CSD87335Q3DT |
|-------------|--------------|--------------|--------------|
| CSD87333Q3D | CSD87334Q3D | CSD87335Q3D | |

Qualification Report Phase 7 Power Block Qual in Amkor P3: CSD87333Q3D, CSD87334Q3D, CSD87335Q3D

Approve Date 06-February-2017

Product Attributes

| Attributes | Qual Device: CSD87333Q3D | Qual Device: CSD87334Q3D | Qual Device: CSD87335Q3D |
|---------------------|-----------------------------|-----------------------------|-----------------------------|
| Assembly Site | AMKOR P3 A/T PHIL | AMKOR P3 A/T PHIL | AMKOR P3 A/T PHIL |
| Package Family | DQZ | DQZ | DQZ |
| Flammability Rating | UL 94 V-0 | UL 94 V-0 | UL 94 V-0 |
| Wafer Fab Supplier | CFAB | CFAB | CFAB |
| Wafer Fab Process | NEXFET-LV 30N10 | NEXFET-LV 30N10 | NEXFET-LV 30N10 |

- QBS: Qual By Similarity
- Qual Device CSD87333Q3D is qualified at LEVEL1-260C
- Qual Device CSD87335Q3D is qualified at LEVEL1-260C
- Qual Device CSD87334Q3D is qualified at LEVEL1-260C
- Device CSD87333Q3D contains multiple dies.
- Device CSD87334Q3D contains multiple dies.
- Device CSD87335Q3D contains multiple dies

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

| Туре | Test Name / Condition | Duration | Qual Device: CSD87333Q3D | Qual Device: CSD87334Q3D | Qual Device: CSD87335Q3D |
|------|------------------------------|---------------------------------|-----------------------------|-----------------------------|-----------------------------|
| MQ | Manufacturability (Assembly) | (per mfg. Site specification) | 3/1/0 - Pass | 3/1/0 - Pass | 3/1/0 - Pass |
| PC | Preconditioning | (per the appropriate pkg level) | - | 3/462/0 | 3/462/0 |
| TC | **T/C -40C/125C | -40C/+125C (500,1000 Cycles) | - | 3/231/0 | 3/231/0 |
| TC | **T/C -55C/125C | -55C/+125C (500,1000 Cycles) | - | 3/231/0 | 3/231/0 |

^{**} Preconditioning was performed for Temperature Cycle as applicable

Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

| Location | E-Mail |
|--------------|--------------------------------|
| USA | PCNAmericasContact@list.ti.com |
| Europe | PCNEuropeContact@list.ti.com |
| Asia Pacific | PCNAsiaContact@list.ti.com |
| Japan | PCNJapanContact@list.ti.com |

⁻ The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles Quality and Environmental data is available at TI's external Web site: http://www.ti.com/Green/Pb-free Status: